

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

IDS/#8

<b>LIST OF PRIOR ART CITED BY APPLICANT</b> (PTO-1449)				ATTY. DOCKET NO. <b>P-093</b>		APPLN. SERIAL NO. <b>09/531,759</b>	
				APPLICANT(S) <b>Yoon Kwan LEE</b>			
				FILING DATE <b>March 20, 2000</b>		GROUP <b>2879</b>	

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 PATENT & TRADEMARK OFFICE

U.S. PATENT DOCUMENTS						
EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE

U.S. PATENT APPLICATION PUBLICATIONS					
	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS

U.S. PATENT APPLICATIONS					
	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS

FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
<i>Wth</i>	* JP 11-096911	04/09/1999	Japan	—	—	X	
<i>Wth</i>	* JP 11-040065	02/12/1999	Japan	—	—	X	
<i>Wth</i>	* JP 11-025867	01/29/1999	Japan	—	—	X	
<i>Wth</i>	* JP 10-228863	08/25/1998	Japan	—	—	X	
<i>Wth</i>	* JP 10-003859	01/06/1998	Japan	—	—	X	
<i>Wth</i>	* JP 09-199029	07/31/1997	Japan	—	—	X	
<i>Wth</i>	* JP 09-161677	06/20/1997	Japan	—	—	X	

OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)	

EXAMINER <i>Chavali Parthiv</i>	DATE CONSIDERED <i>6/30/03</i>
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